

<b>Notice of References Cited</b>	Application/Control No. 10/814,369	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner /Yonel Beaulieu/	Art Unit 3661	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,203,577	04-2007	Gunn et al.	701/3
*	B	US-7,256,710	08-2007	Mumaw et al.	340/973
*	C	US-7,321,318	01-2008	Crane et al.	340/971
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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